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Special issue: Statistical techniques in pattern recognition

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SPECIAL ISSUE:

Statistical Techniques in Pattern Recognition

Pattern recognition is one of the most important and challenging fields of artificial intelligence. Statistical pattern recognition was together with syntactical pattern recognition at the cradle of pattern recognition as a newly emerged scientific field already many years ago. Though since then many other branches have developed and pattern recognition somewhat diversified, statistical pattern recognition remains one of the core disciplines. A recent revival of interest has been noticed not only from researchers in other branches of pattern recognition community but also from other disciplines of mathematics and informatics.

This special issue of *Kybernetika* is devoted to selected papers from the “Workshop on Statistical Techniques for Pattern Recognition” (STIPR’97). This workshop was jointly organized by the International Association for Pattern Recognition Technical Committee 1 on Statistical Techniques in Pattern Recognition (<http://www.utia.cas.cz/TC1/>), ÚTIA, the European Research Consortium for Informatics and Mathematics (ERCIM), and the Czech Pattern Recognition Society. It was held in Prague on June 9–11, 1997. The workshop was sponsored by ERCIM and UNIPETROL a. s.

STIPR’97 was attended by 35 participants from fifteen countries, six participants came from outside of Europe. Three invited lectures were given by outstanding experts Prof. Josef Kittler (U.K.), Dr. Robert P.W. Duin (The Netherlands), and Dr. Andre Gagalowicz (France). Thirty technical papers presented orally were grouped into four thematic blocks: Feature Selection and Extraction, Classification Methods, Neural Nets and Fuzzy Approaches, Applications.

Though the participants to the Workshop were from 15 countries, they established quickly a really friendly and working atmosphere and made a substantial contribution towards the development of the field. Our main objective has been achieved – the community of researchers working in various aspects of statistical pattern recognition has been strengthened and new important scientific links have been created.

As all the papers for STIPR’97 were already reviewed by the international Programme Committee and published in its proceedings, it need not be stressed that selecting the papers for this special issue of *Kybernetika* was not an easy task (full titles of the 21 selected papers, with inclusive pagination, can be found on the next page). It is my duty and pleasure at the same time to thank all those colleagues who have helped to select the papers and to prepare this special issue. My thanks are also due to the Managing Editor of *Kybernetika* Dr. K. Sladký for his invaluable help and to Mrs. I. Marešová for careful editing and typing of all the papers.

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